

Topography evaluation methods for concrete surface

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Surface preparation

What? Why? How?

polishing



sandblasting



scarification



Water-jetting



scabbling



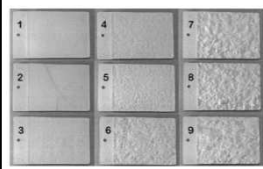


Surfology: techniques and principles

1. Preparation of concrete surface
Needs for knowledge
2. Topography evaluation
Parameters and techniques
3. Methodology comparison
What is the best technique?
4. Conclusions and propectives
Extension of CSP's

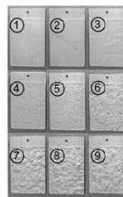
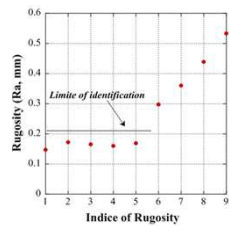
Topography: Concrete Surface Profiles

Reference ICRI plates and comparison with roughness on site



Surface preparation methods	CSP
Detergent scrubbing	1
Low-pressure water cleaning	1
Acid etching	1-3
Grinding	1-3
Abrasive (Sand) blasting	2-5
Steel shotblasting	3-8
Scarifying	4-9
Needle scaling	5-8
Hydrodemolition	6-9
Scabbling	7-9
Flame blasting	8-9
Milling/rotmilling	9

Topography evaluation: Concrete Surface Profiles



Opto-morphometric method

- the limit of identification depends on the camera characteristic.
- for $Ra > 0.250$ mm, differentiation is satisfactory

Perez, F., Courard, L., Bissonnette, B., Garbacz, A. and Gorka (2005) ICCRR 2005: 1015-1020

Topography evaluation : Sand Patch Test

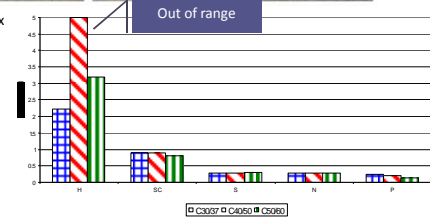
ASTM E965
EN 13036-1: 2002
EN 1766: 2000



Surface Rough Index

$$SRI = 4V/\pi D^2$$

H = water-jetting
SC = scabbling
S = sandblasting
P = polishing



Topography evaluation : mechanical profilometry



Technical characteristics

- system capacity: 1000 by 1000mm
- surface of measurement : 30 by 30mm
- shape of the stylus: spherical
- diameter of the stylus: 6µm and 1.5mm
- step of measurement: 300µm

6 µm
1.5 mm



Courard L., Garbacz A., Gorka M. (2004) ICPIC Berlin: 125-132

Topography evaluation : optical profilometry

Equipments to measure surface topography

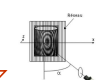


Mechanical profiling
Measuring area : 200x200 mm
Shape of the stylus: truncated cone
Diameter of the stylus: 1 mm
Path of measurement: 1 mm



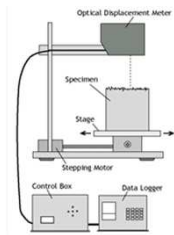
Atos I 3D Digitizer
Fringe patterns
Measuring area:
120x100 - 1000x800 mm²
Spatial resolution: 0,04-1 mm

Mathematical
treatment

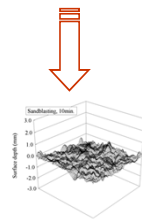


Topography evaluation : optical profilometry

Equipments to measure surface texture



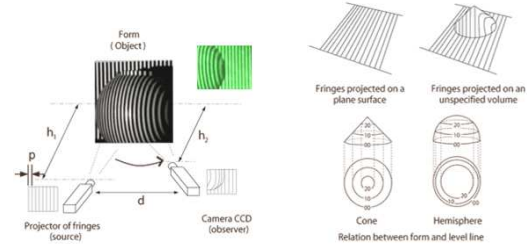
Laser profiling
method based on a laser distance measurement by optical displacement meter, principle based on optical triangulation, a lens focuses the spot of reflected laser light onto a photodetector, which generates a signal that is proportional to the spot's position on the detector



Fukuzawa, K., Mitsui, M. and Numao, T. (2001) ICPI01 Honolulu

Topography evaluation : optical profilometry

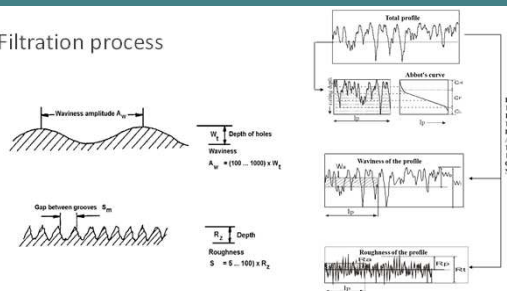
Deformation of parallel and periodic fringes (level line)



Perez, F., Courard, L., Bissonnette, B., Garbacz, A. and Garka (2005) ICRRR 2005: 1015-1020

Topography evaluation : descriptive parameters

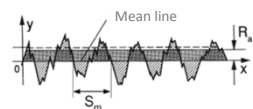
Filtration process



Courard L., Nélis M. (2003) Mag. Concr. Res., 55(4): 355-366

Topography evaluation : descriptive parameters

Parameters	Definition
X_t	total height of the profile
X_v	maximum depth of the profile (holes)
X_s	maximum height of the profile (peaks)
X_a	arithmetic mean of the deviation of the profile from the mean line
X_q	quadratic mean of the deviation of the profile from the mean line
S_s	skewness of surface height distribution
S_m	mean spacing between profile peaks at the mean line, measured over the assessment length
C_r, C_v, C_u	Bearing ratio parameters



Courard L., Nélis M. (2003) Mag. Concr. Res., 55(4): 355-366

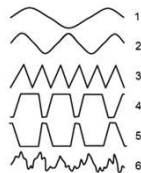
Topography evaluation : descriptive parameters

Xa parameter seems to be accurate ...

More than 2 parameters are needed to obtain a correct description of waviness/roughness

Profiles 4 and 5 have same S_m

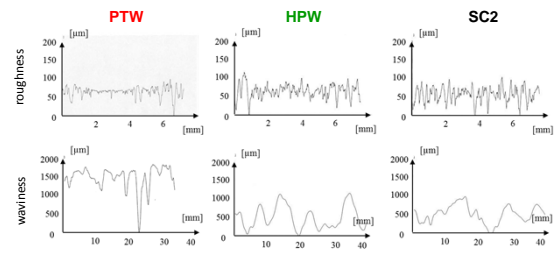
Profiles 1 to 6 have same R_a



Consequences on adhesion are probably different ...

Topography evaluation : descriptive parameters

Mechanical evaluation



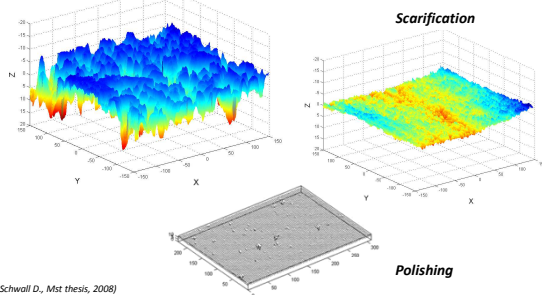
Garbacz A., Courard L., Kostana K. (2006) Materials Characterization, 56: 281-289

Topography evaluation : descriptive parameters

Water jetting

Optical evaluation

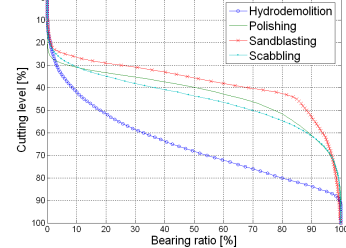
Scarification



(Schwall D., Mst thesis, 2008)

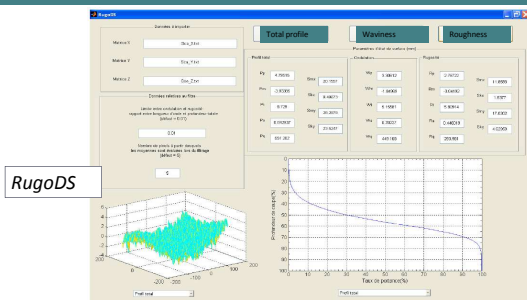
Topography evaluation : descriptive parameters

Abbott's curve C40/50 (Profile)



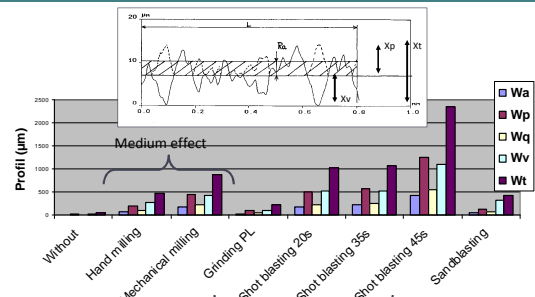
Courard L., Garbacz A., Piotrowski T. (2008) Challenges for civil construction, CCC08, Porto

Topography evaluation : calculation software



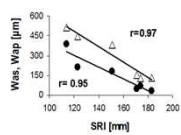
(Schwall D., Mst thesis, 2008)

Surfology: surface preparation techniques

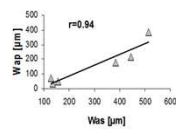


Courard L., Garbacz A., Piotrowski T. (2008) Challenges for civil construction, CCC08, Porto

Topography: comparison



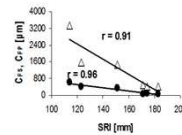
Surface Rough Index vs arithmetic mean of waviness for mechanical (p,Δ) and laser (s,•) profilometers



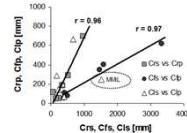
Comparison of mean waviness for mechanical (p) and laser (s) profilometers

Garbacz A., Courard L., Kostana K. (2006) Materials Characterization, 56: 281-289

Topography: comparison



Surface Rough Index vs Abbott's parameters for mechanical (p,Δ) and laser (s,•) profilometers



Abbott's parameters for mechanical (p,Δ) and laser (s,•) profilometers

Garbacz A., Courard L., Kostana K. (2006) Materials Characterization, 56: 281-289

Topography evaluation : conclusions

CSP is not really accurate for concrete surface preparation techniques (water-jetting, jack hammering, ...)

the geometrical parameters determined for both macroscopic level (SRI value) and microscopic level (RS, RL ratios and waviness parameters) generally indicate that a higher roughness was obtained after shot blasting for 45s and a lower roughness by grinding,

there is a quite good correlation between SRI and statistical parameters measured by mechanical (optical) and laser profilometry,

mean waviness or Abbott's parameters are the most appropriated parameters for roughness (waviness) evaluation.

... we are working on extending applicability of CSP (higher roughness)

Acknowledgements

Thanks for your attention...

*... and to my co-authors who allowed
me to come to Cape Town!*

